

Application/Control No.	Applicant(s)/Pate Reexamination	ent under
10/580,047	MURATORE ET	AL.
Examiner	Art Unit	
SVED ZAIDI	2616	

	SEARCHED				
Class	Subclass	Date	Examiner		
455	417	6/6/2008	SZ		
455	418	6/6/2008	SZ		
455	414.1	6/6/2008	SZ		

INTERFERENCE SEARCHED					
bclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	6/6/2008	SZ		
Inventor : MURATORE ET AL.	6/6/2008	SZ		
IEEE Xplore Database(http://ieeexplore.ieee.org/Xp lore/DynWel.jsp)	6/6/2008	SZ		
(455/417 455/418 455/414.1).ccls.	6/6/2008	SZ		
Consulted with SPE Nick Corsaro	6/6/2008	SZ		